

METHOD FOR QUANTIFYING SAFE  
OPERATING AREA FOR BIPOLAR  
JUNCTION TRANSISTOR  
Inventors: Kim et al.  
Atty. Docket No. P05779

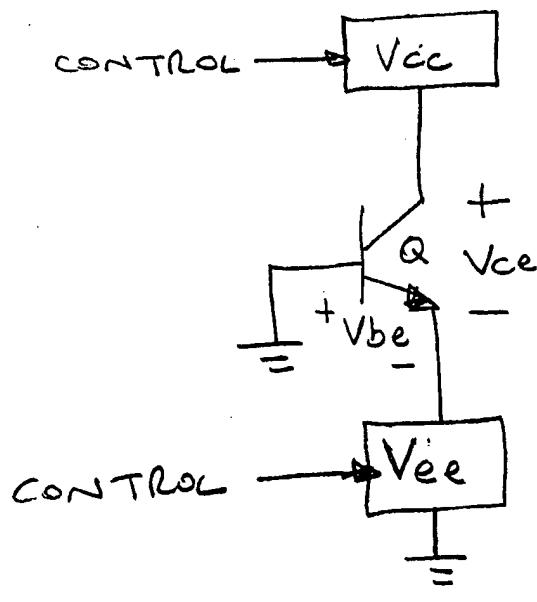


FIGURE 1A  
(PRIOR ART)

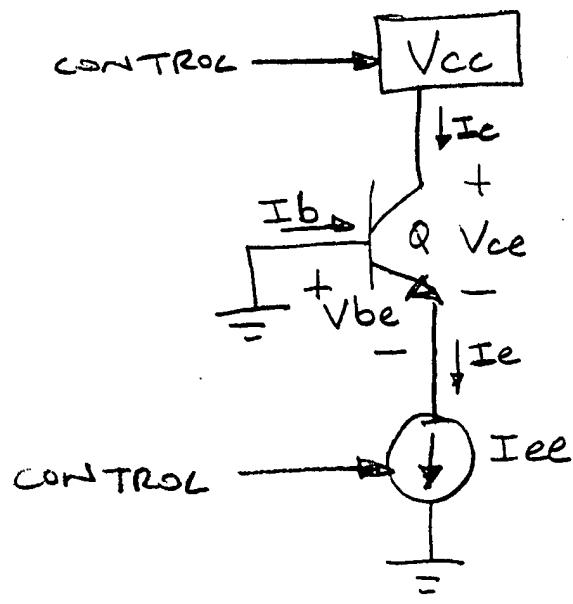


FIGURE 2A  
(PRIOR ART)

METHOD FOR QUANTIFYING SAFE  
OPERATING AREA FOR BIPOLAR  
JUNCTION TRANSISTOR  
Inventors: Kim et al.  
Atty. Docket No. P05779

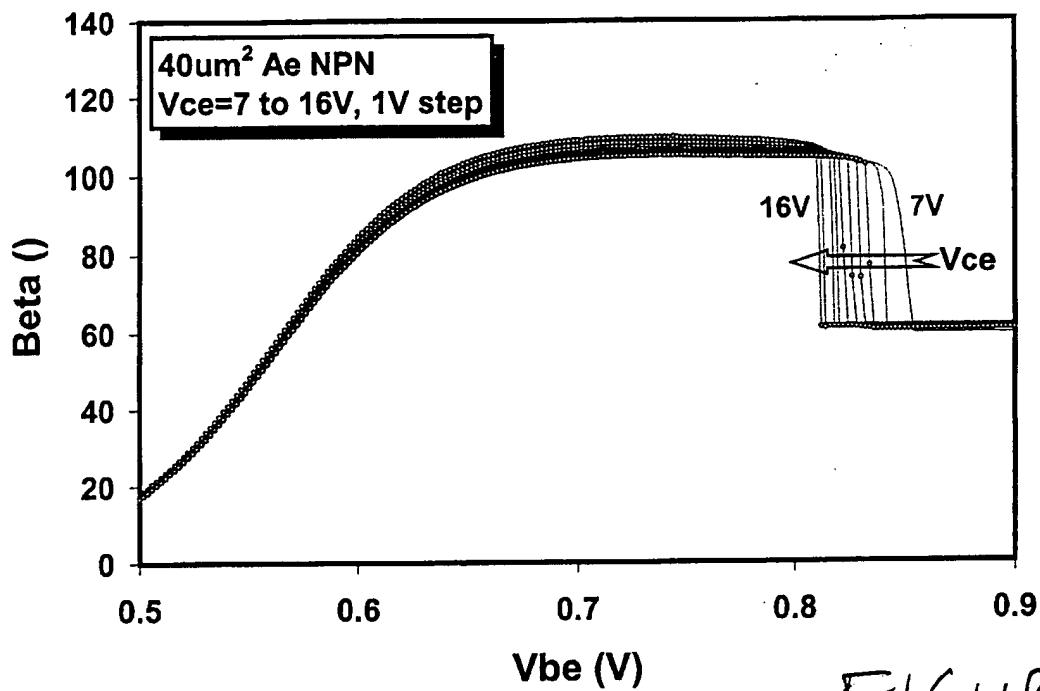


FIGURE 1B  
(PRIOR ART)

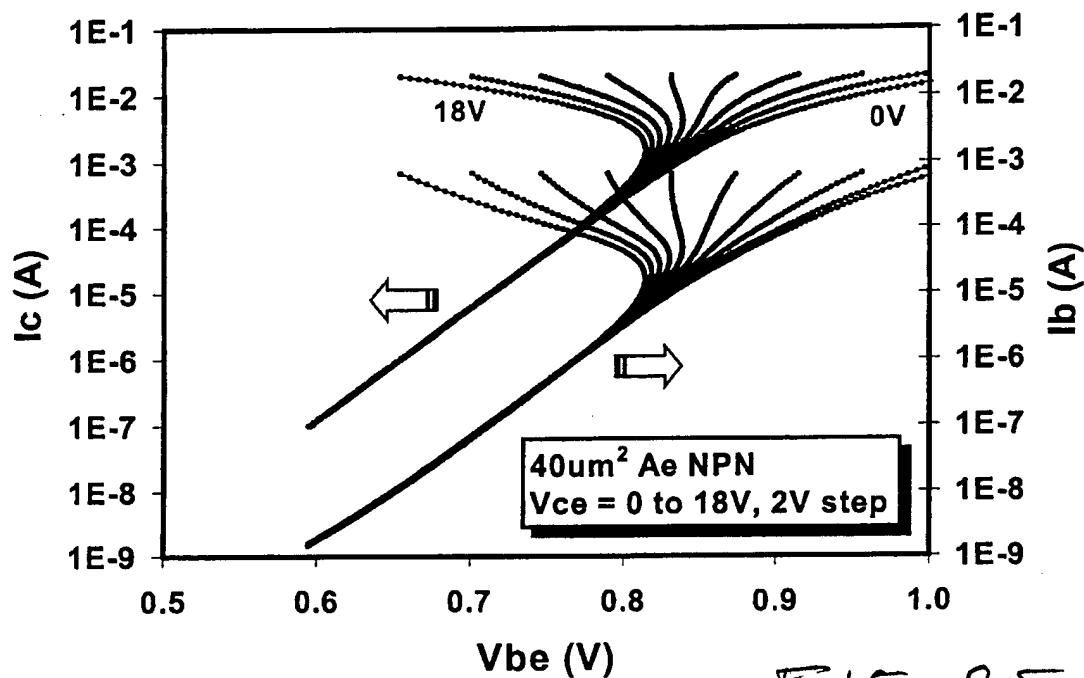
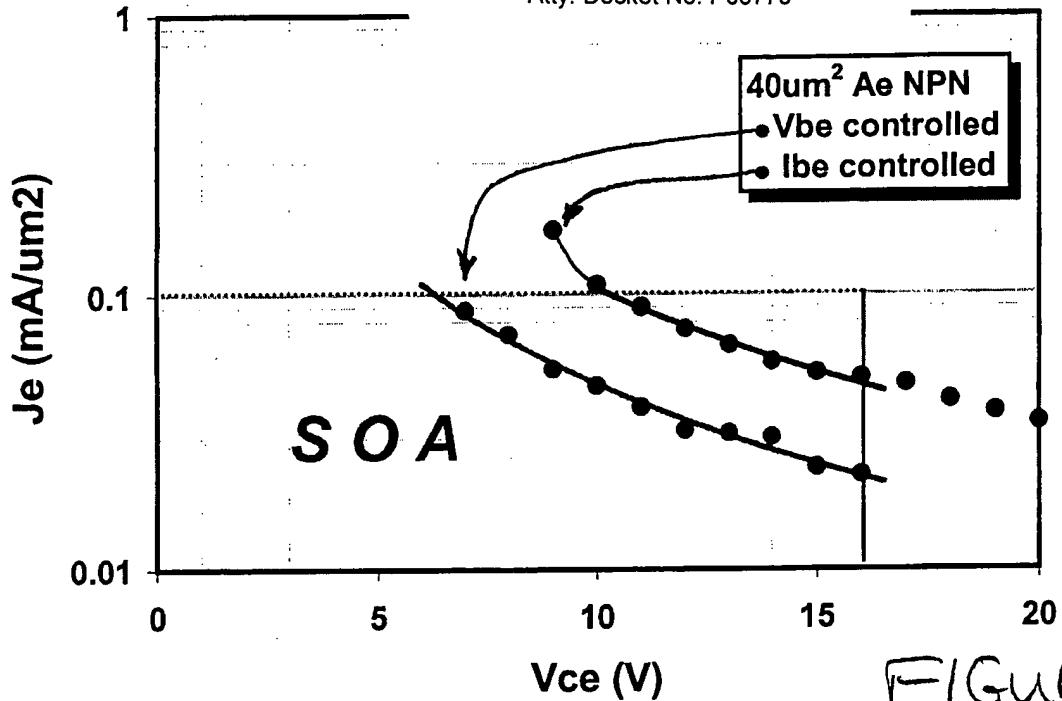


FIGURE 2B  
(PRIOR ART)

METHOD FOR QUANTIFYING SAFE  
OPERATING AREA FOR BIPOLAR  
JUNCTION TRANSISTOR  
Inventors: Kim et al.  
Atty. Docket No. P05779



### FIGURE 3 (PRIOR ART)

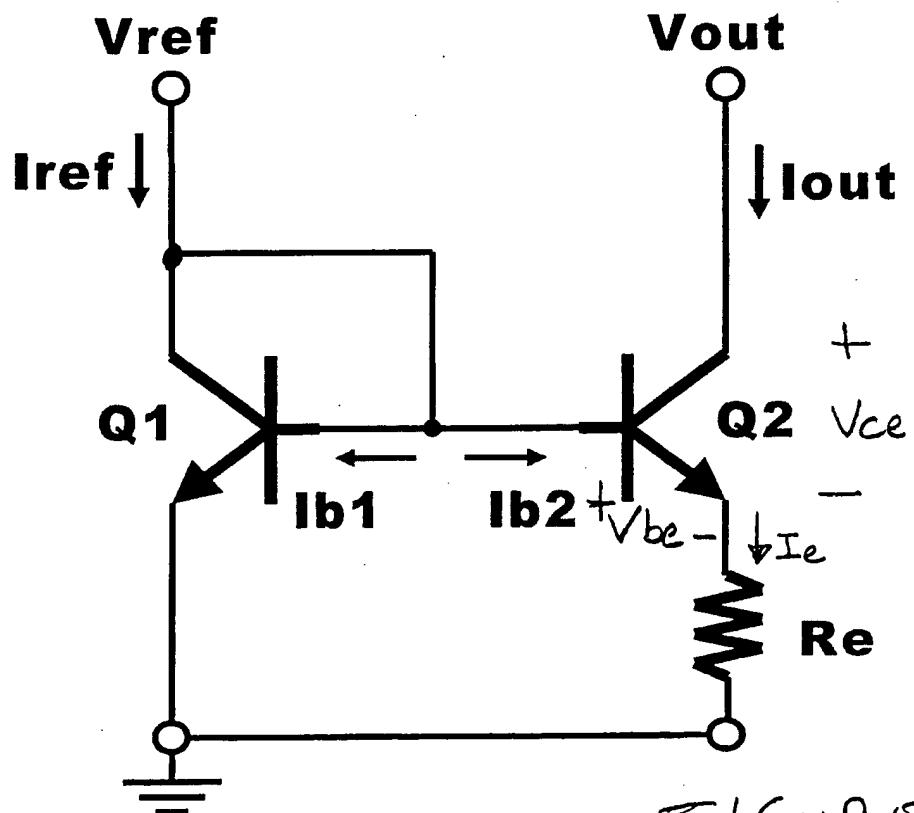


FIGURE 4

METHOD FOR QUANTIFYING SAFE  
OPERATING AREA FOR BIPOLAR  
JUNCTION TRANSISTOR  
Inventors: Kim et al.  
Atty. Docket No. P05779

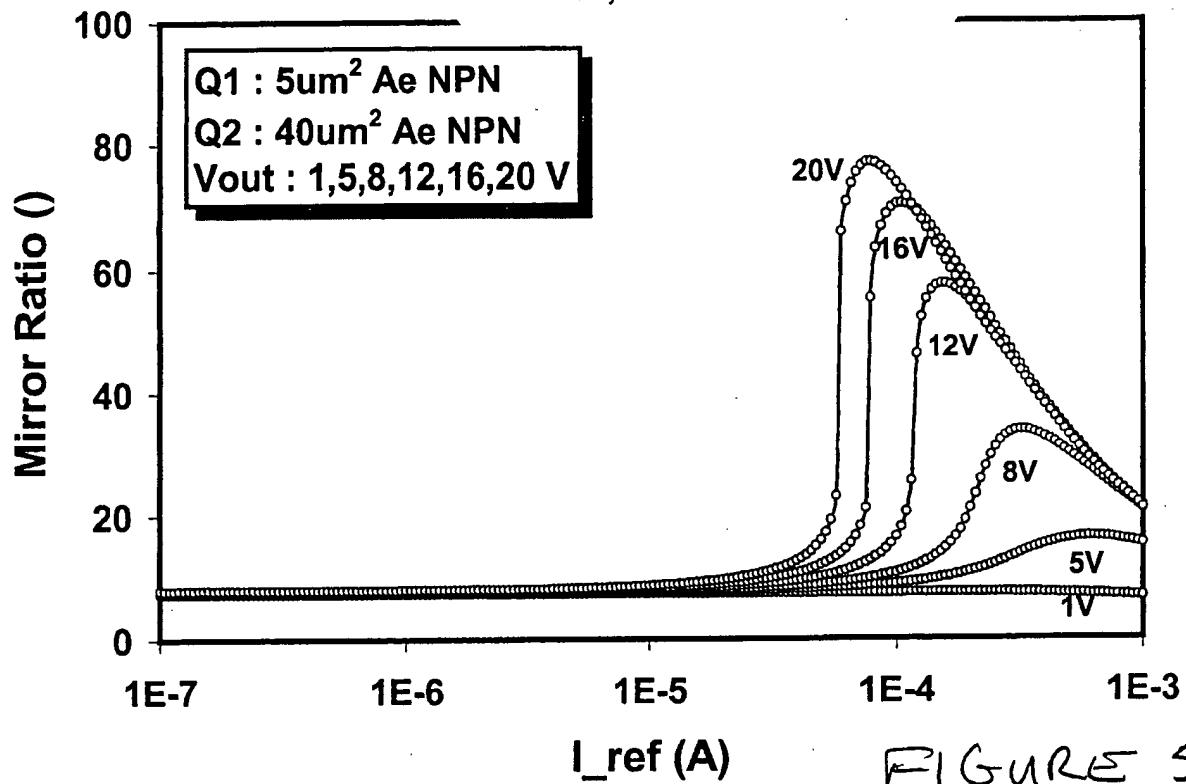


FIGURE 5

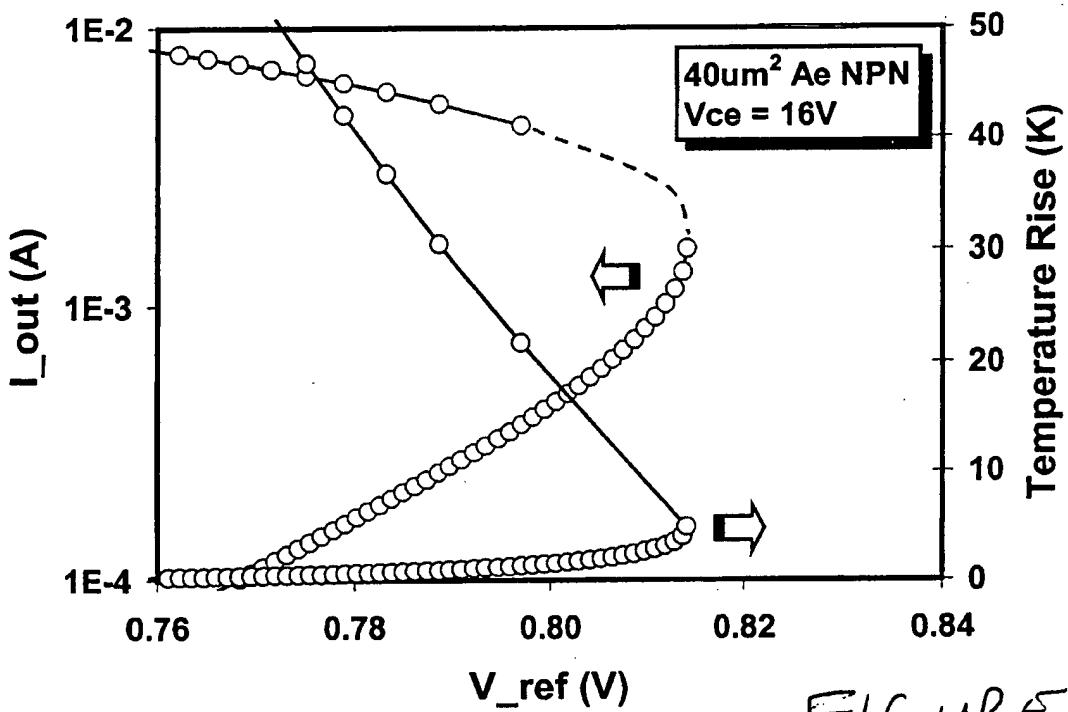
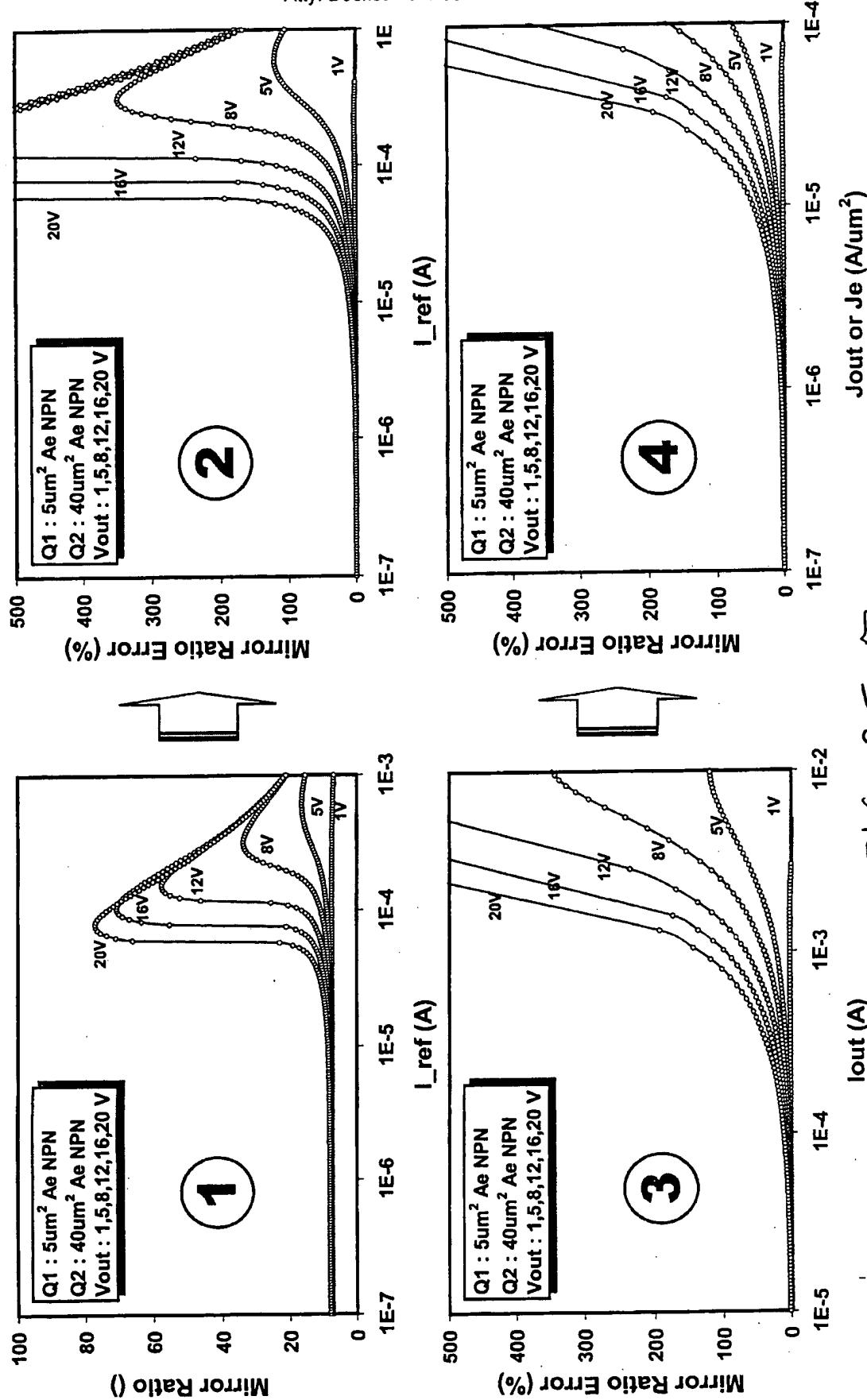


FIGURE 6

METHOD FOR QUANTIFYING SAFE  
OPERATING AREA FOR BIPOLAR  
JUNCTION TRANSISTOR  
Inventors: Kim et al.  
Atty. Docket No. P05779



METHOD FOR QUANTIFYING SAFE  
OPERATING AREA FOR BIPOLAR  
JUNCTION TRANSISTOR  
Inventors: Kim et al.  
Atty. Docket No. P05779

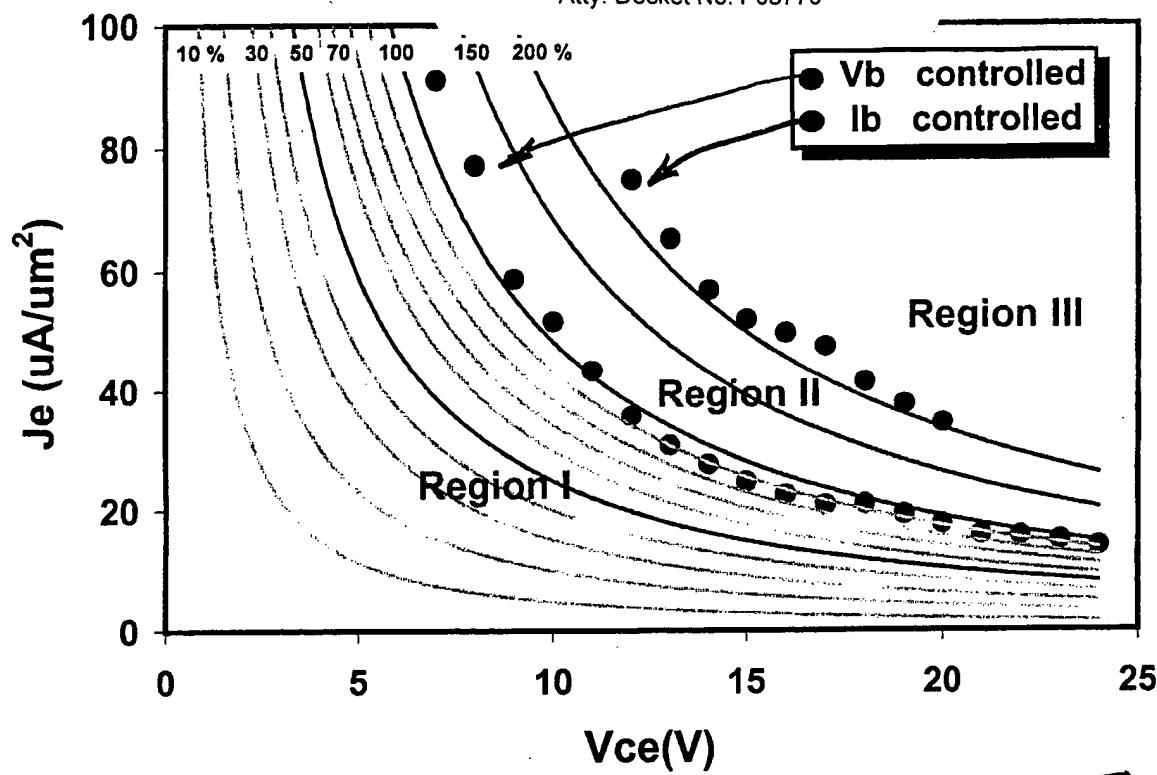


FIGURE 8

METHOD FOR QUANTIFYING SAFE  
OPERATING AREA FOR BIPOLAR  
JUNCTION TRANSISTOR  
Inventors: Kim et al.  
Atty. Docket No. P05779

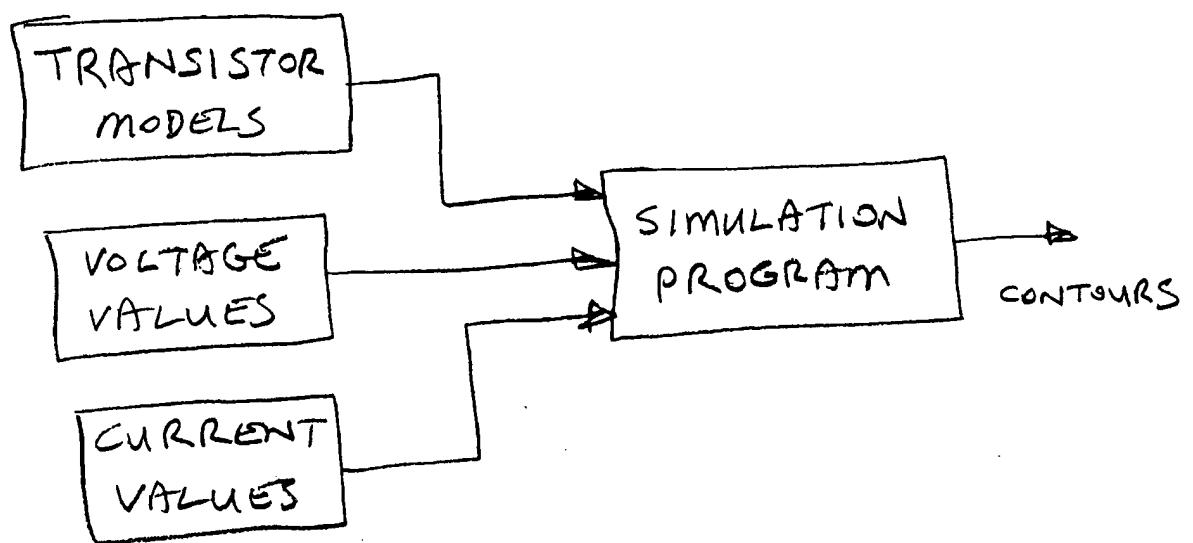


FIGURE 9